



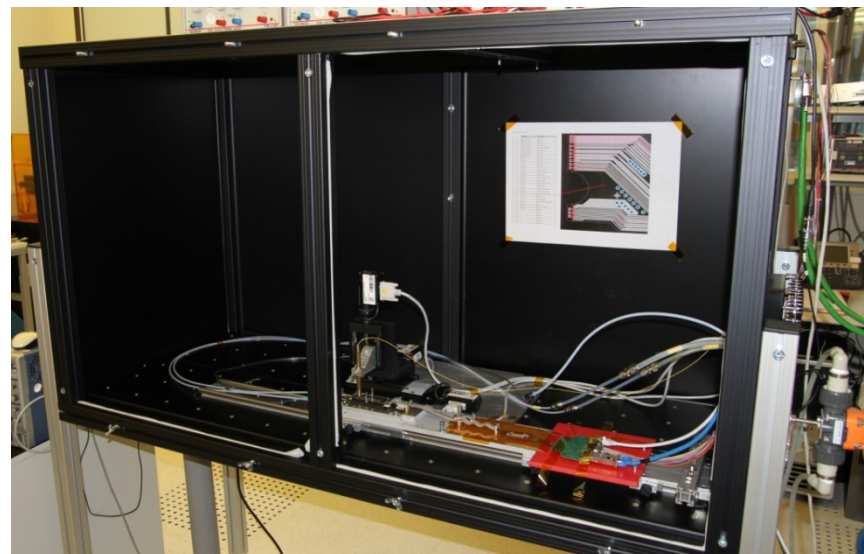
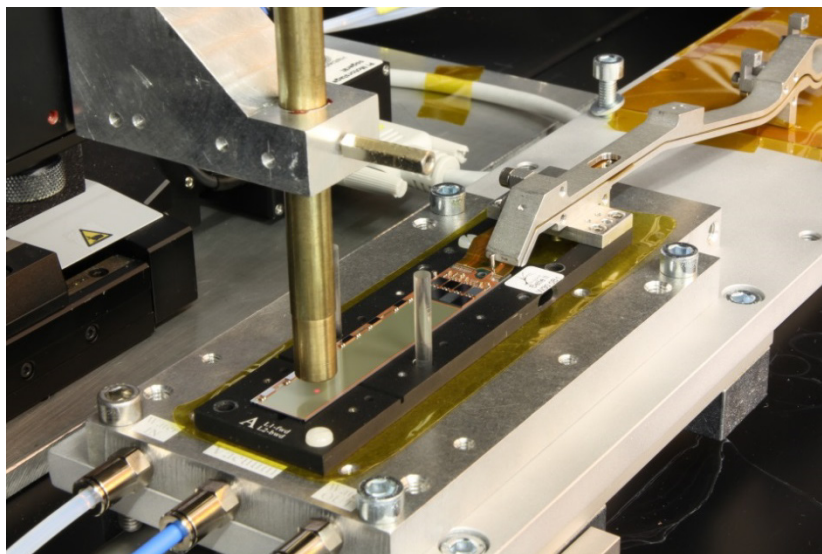
PXD9 Pilot Module

Status Verification of the Metal Routing

PXD SeeVogh – November 10, 2015

Felix Müller, Christian Koffmane for the Testing Crew

● PXD9 Pilot Module – Verification of the Metal Routing



Module operated @ 250MHz (128ns per row)

- power-up ASICs – sanity check voltages + currents ✓
- configure ASICs via JTAG ✓
- boundary Scan: PASS (no faults in the digital I/Os) ✓
- DHPT serial link – parameters of the pre-emphasis ✓
- DCD <-> DHPT communication – timing adjustment ✓
- **sampling point scan**
- optimize DCD analogue performance (IPSource/2, IFBPBias, RefIn)

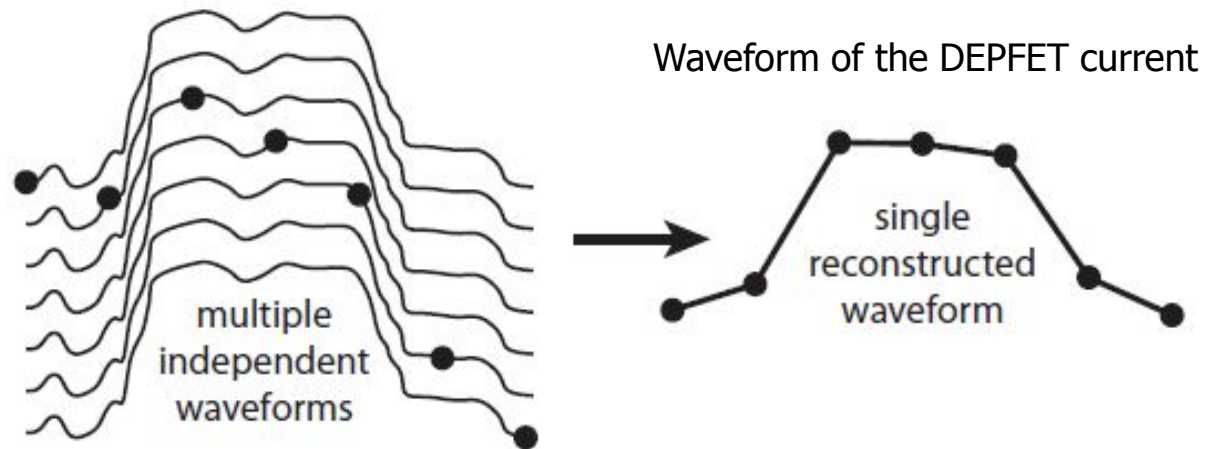
- 2 outer backward modules are assembled with kapton
- 1 outer forward module is prepared for the assembly on Hybrid7

● Sampling Point Scan

Time resolved measurements with DHPT and DCD

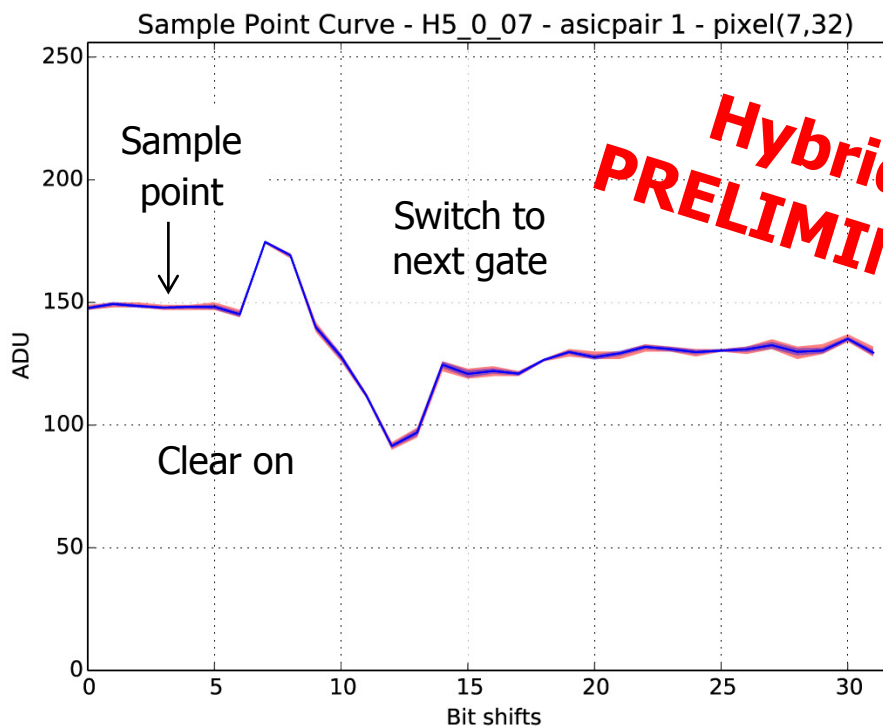
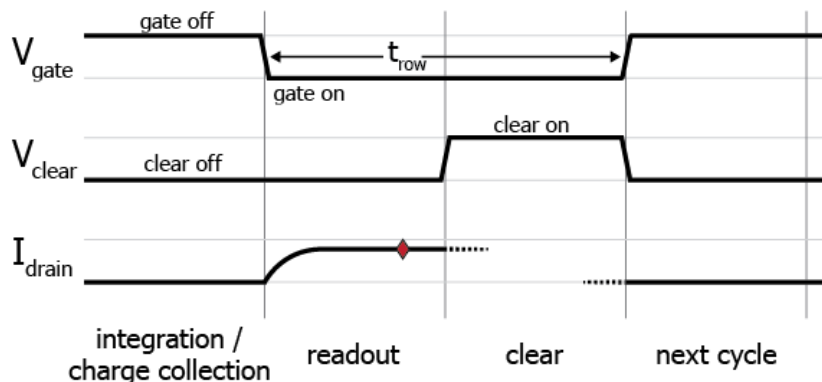
Applying a technique called sequential sampling a continuous time waveform of the DEPFET current can be measured

- From a periodic and stable input a single sample is taken
- The sample point is shifted by ΔT
- The single samples are assembled to form a combined waveform
- Averaging can be used to suppress electronic noise



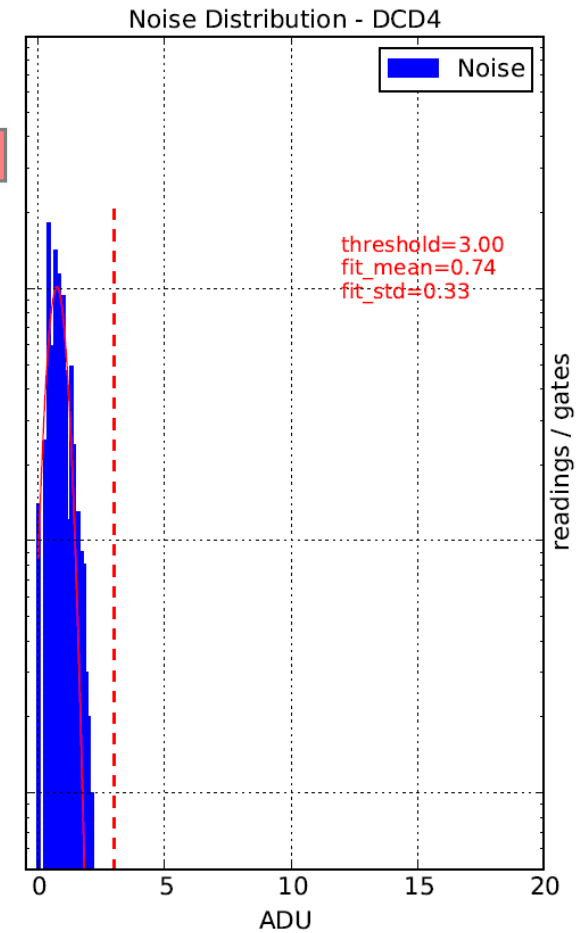
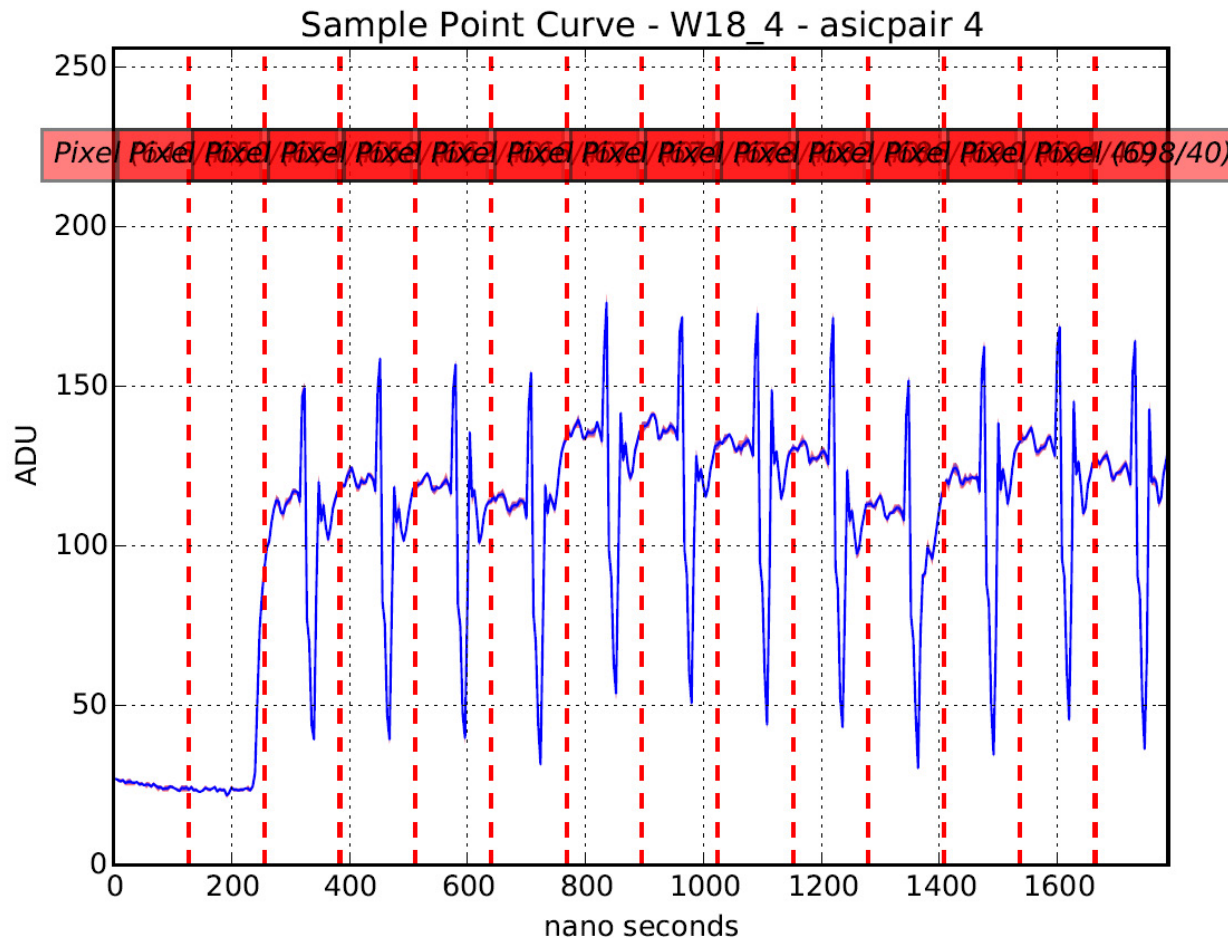
● Sampling Point Scan

- Sampling the DEPFET current at the correct point of time is extremely important
- The scan is currently implemented with DHPT as controller for the timing
- Step size coarse = 4ns
- Step size fine = $\sim 250\text{ps}$



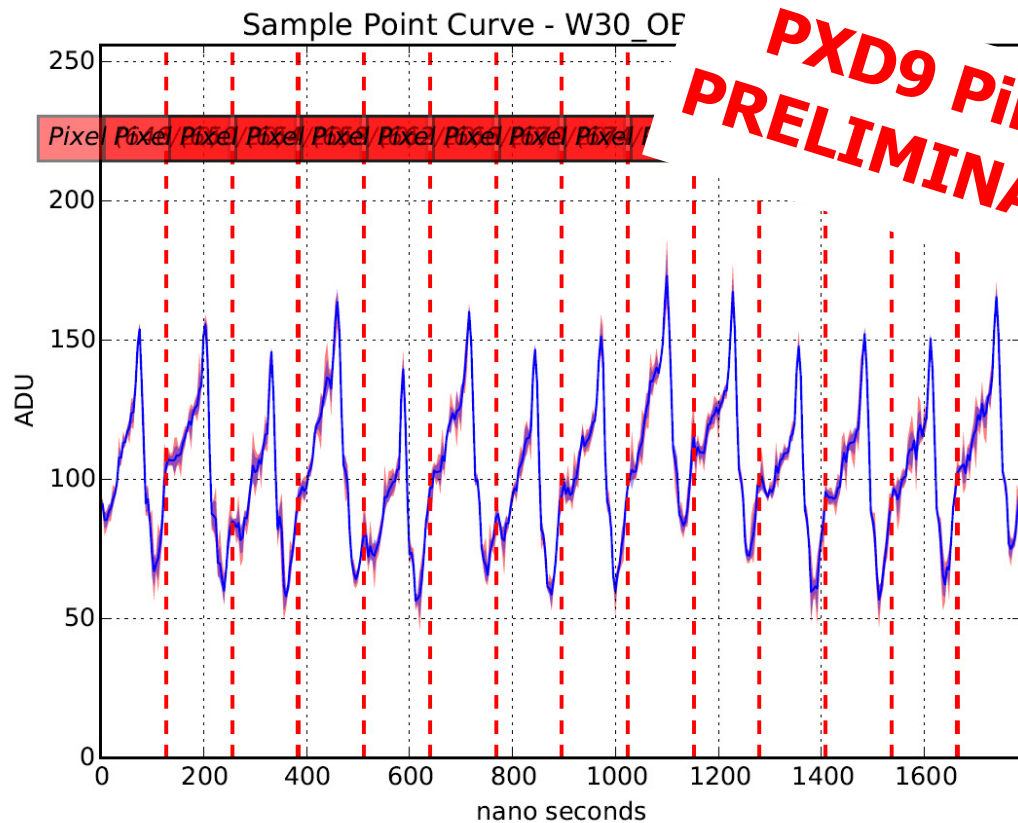
- Sampling point curve using Hybrid5 DHPT/DCDB4 + small PXD9 matrix @ 250MHz
- 1 bit shift = 4ns

EMCM W18-4: Sample Point Scan and Noise (small PXD9)



● Sampling Point Scan

- Same sequence as for EMCM applied
- No plateau for stable current sampling @ 128ns per row
- Timing of a subset of the rows changed to 384ns (32 out of 192)
- Work in progress: scan of the switcher Strobe-Clear signal with respect to Switcher-Clock and Strobe-Gate



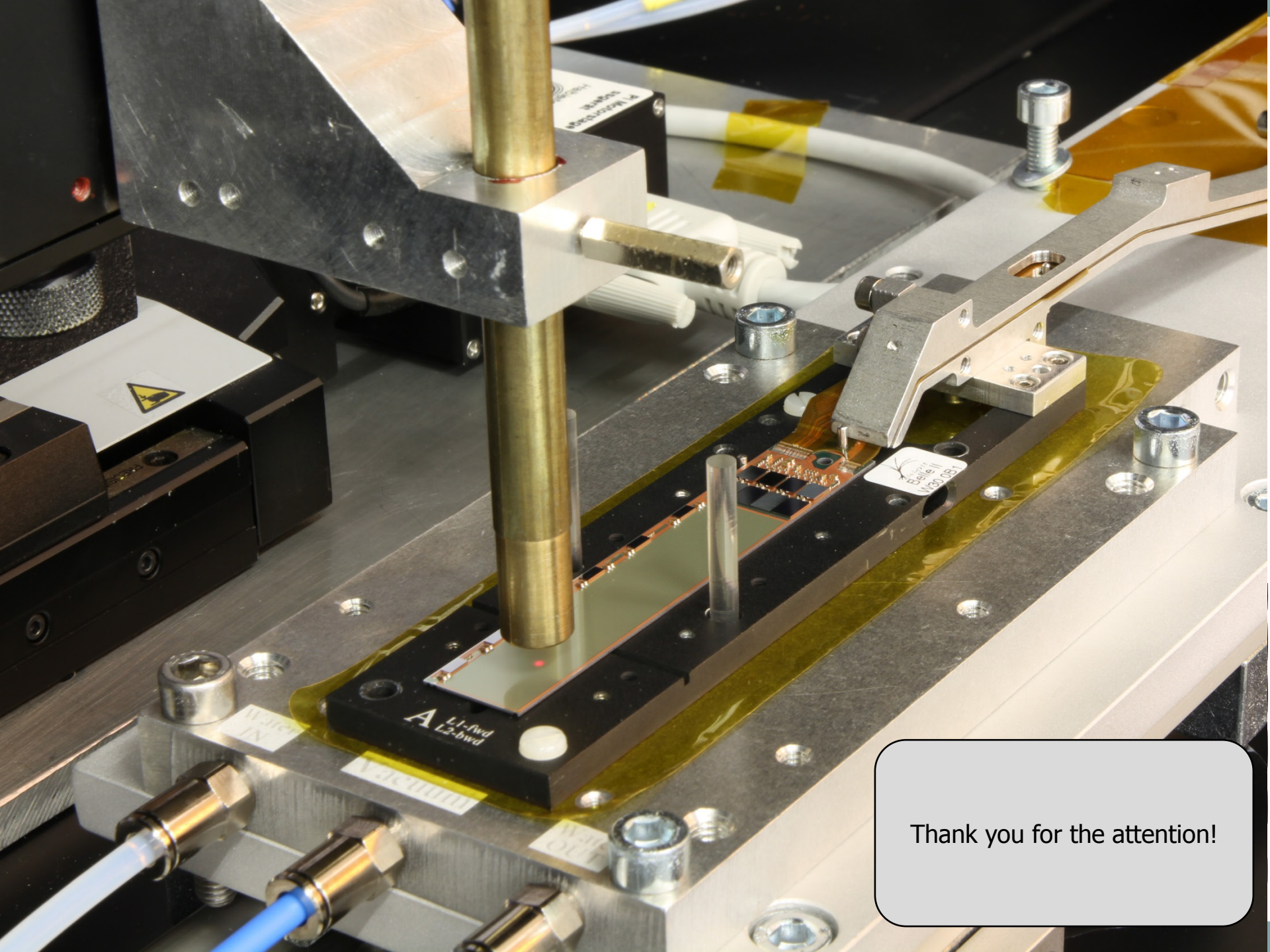
128ns per row

- We need more time to understand the sampling point scans
- Measurements @ full speed are delayed
- Still we would like to keep the date for a expert F2F meeting @ HLL in cw. 48

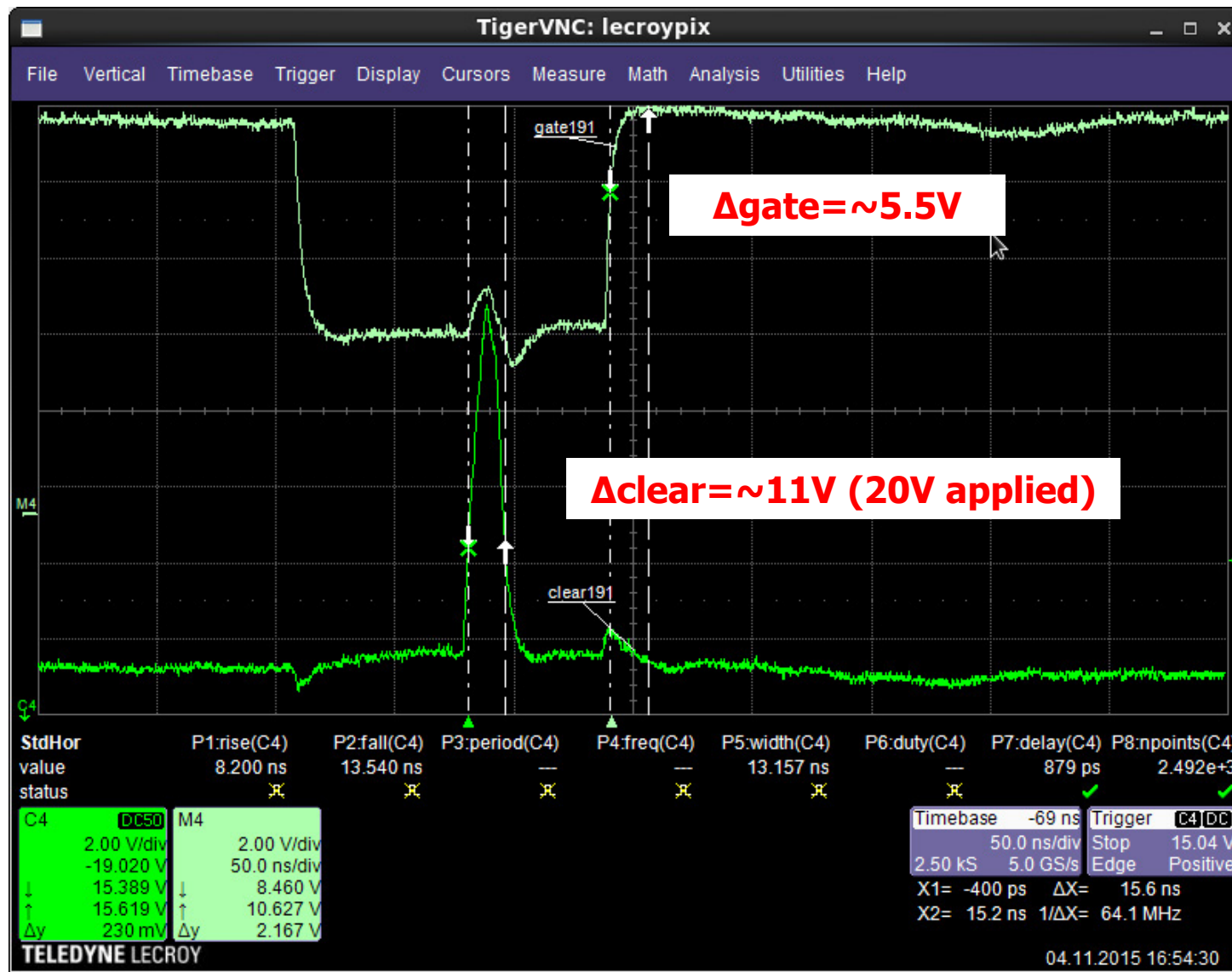
● PXD9 Pilot Verification Plan

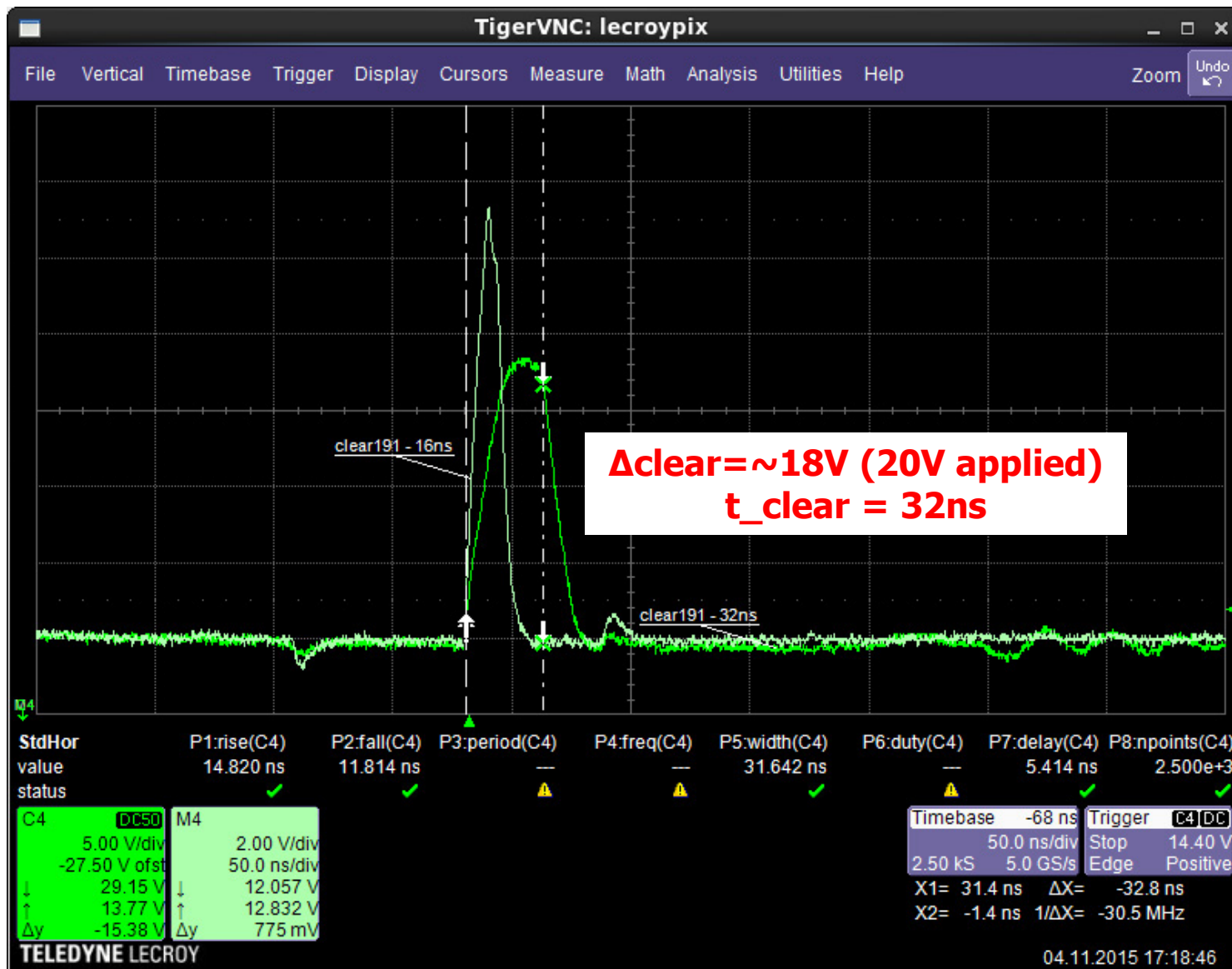


	26.-30. Oct	2.-6. Nov	9.13. Nov	16.-20. Nov	23.-27. Nov	30. Nov - 4.Dec.	Dec. 7th
CW	44	45	46	47	48	49	50
HLL (pxdtest2)	sampling point scan			increase to nominal freq.	gated mode		Go for PXD9 metallization or agreement on the necessary changes
	pedestal/noise all DCDs			DHPT serial link - IBERT/oscilloscope	pedestal compression		
				DCD <-> DHPT (delay)	Cd109 spectrum		
				sampling point scan	Laser spot		
				pedestal/noise all DCD	F2F Meeting @ HLL		
				zero suppressed data			
HLL (pxdtest4)			Preparation Gated Mode Test EMCM		Hybrid 7 Testing to verify OF/IB balcony and EOS layout		



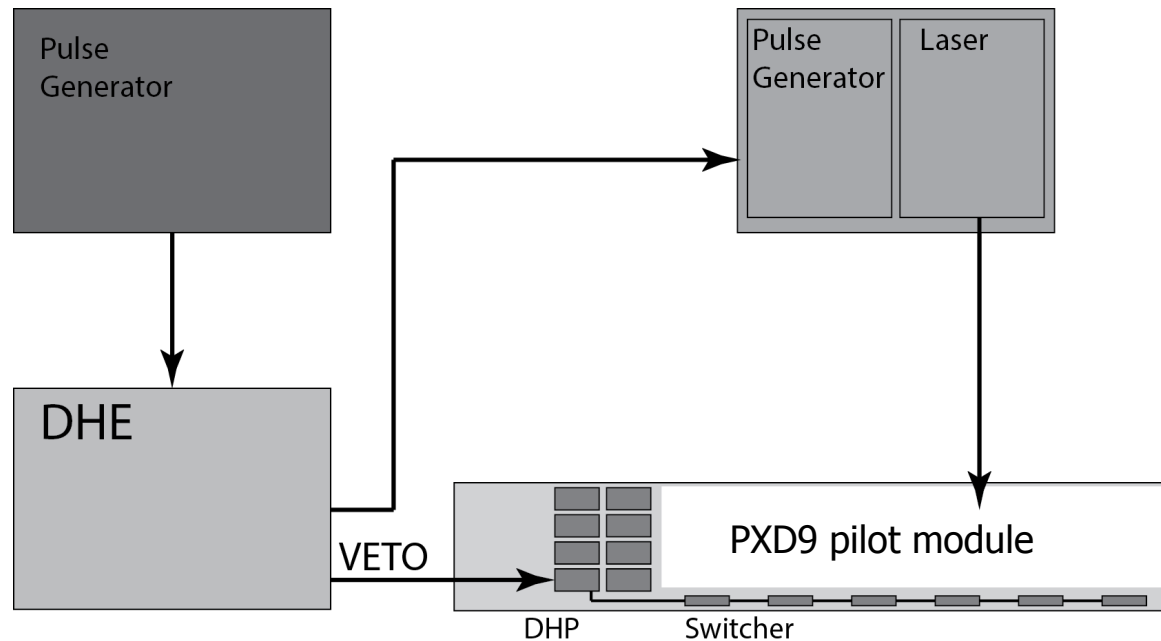
Thank you for the attention!





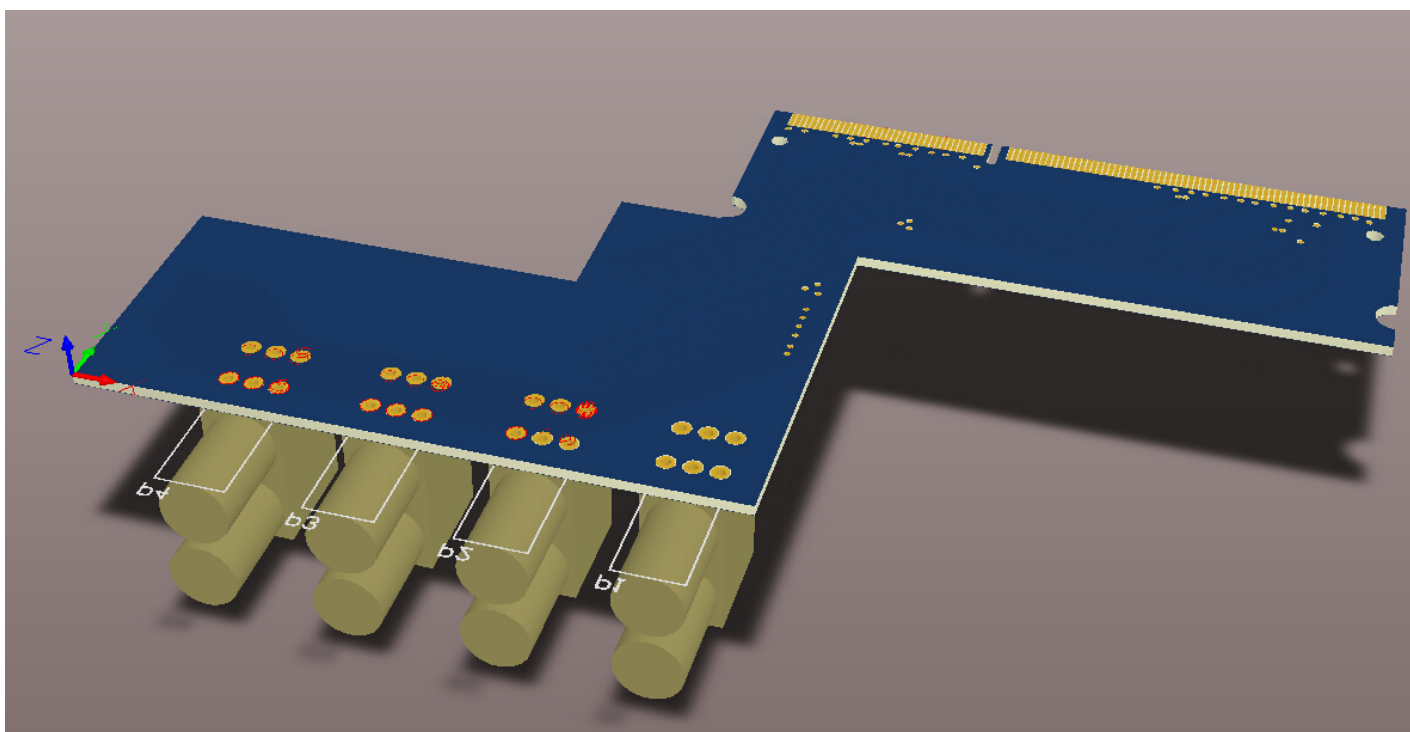
● Gated Mode Verification

- DHE receives VETO trigger from external pulse generator and forwards it to the DHPT
- the DHPT jumps from the current sequencer memory address to a dedicated address where the Gated Mode sequence is defined
- via the control lines (StrG, StrC, CLK) the Switcher is programmed into Gated Mode – the timing can be chosen in steps of $\sim 3.3\text{ns}$
- separated in 4 groups of Switcher output channels all the Clear lines are switched to the ClearOn potential, the Gate line keep the GateOff potential
- the DHE generates a trigger for a laser to verify that the gating works



● Gated Mode Verification

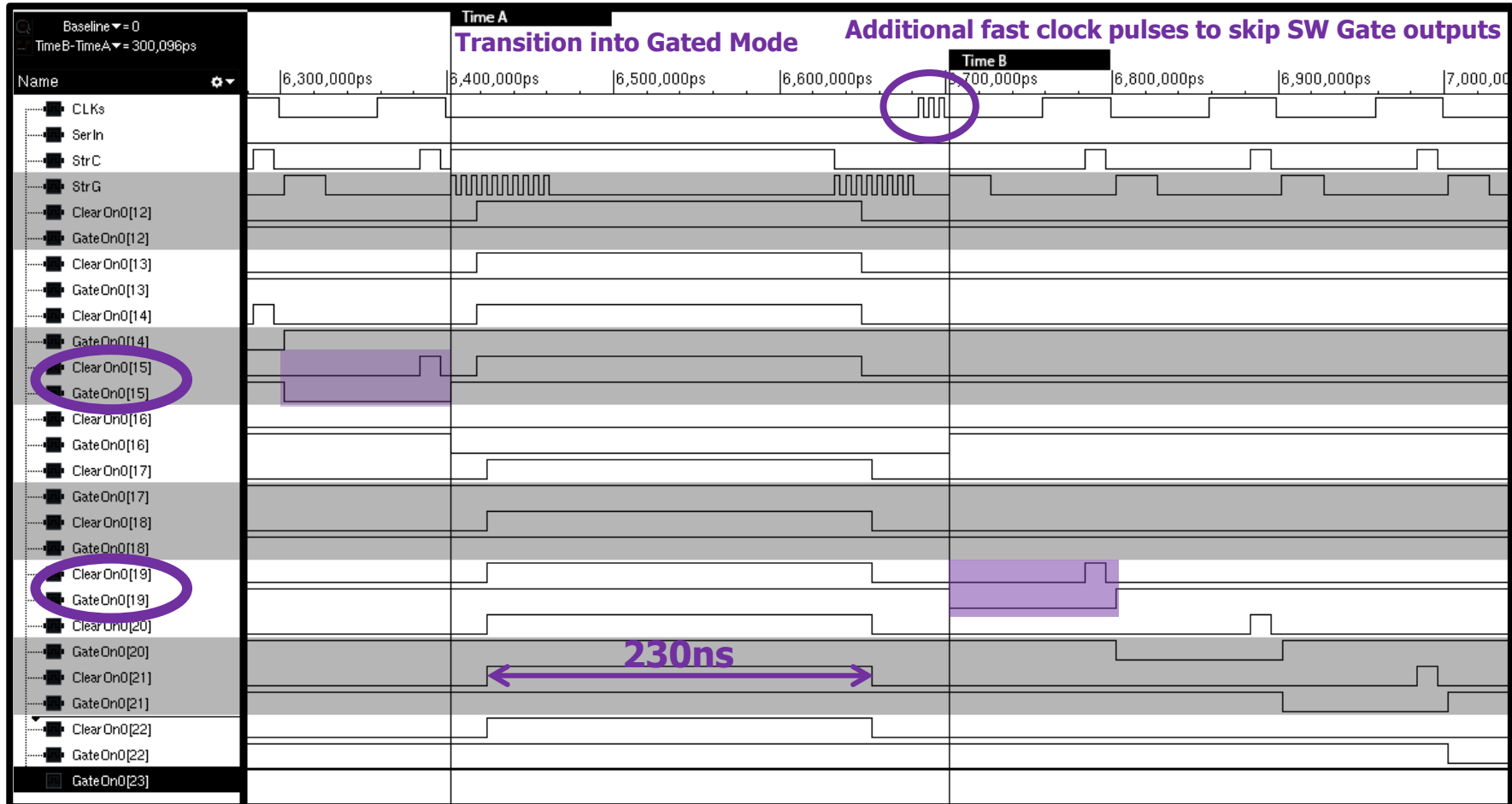
- DHE adapter board for external VETO trigger is available and tested
- dedicated firmware for the Gated Mode test in the lab also available and tested @ TUM
- system test with EMCM and small PXD9 matrix planned for next week @ HLL



Unfortunately I missed to take a photo ...

Gated Mode Verification

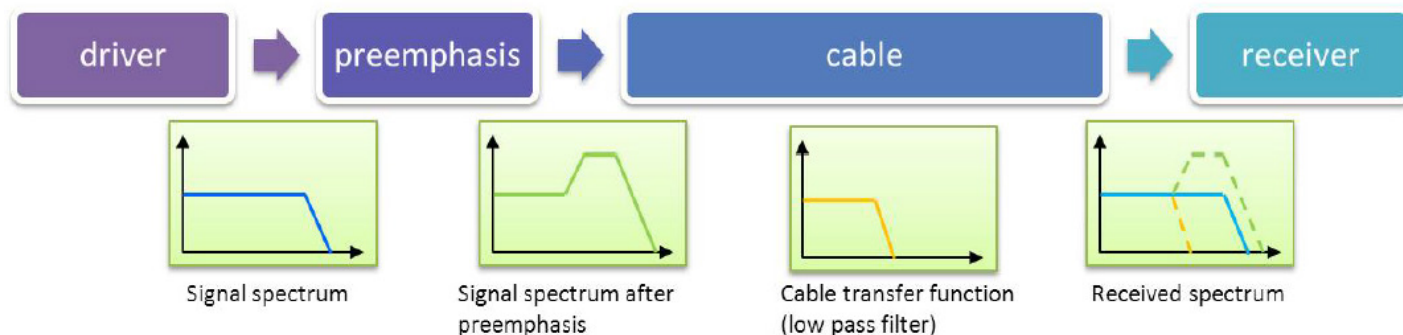
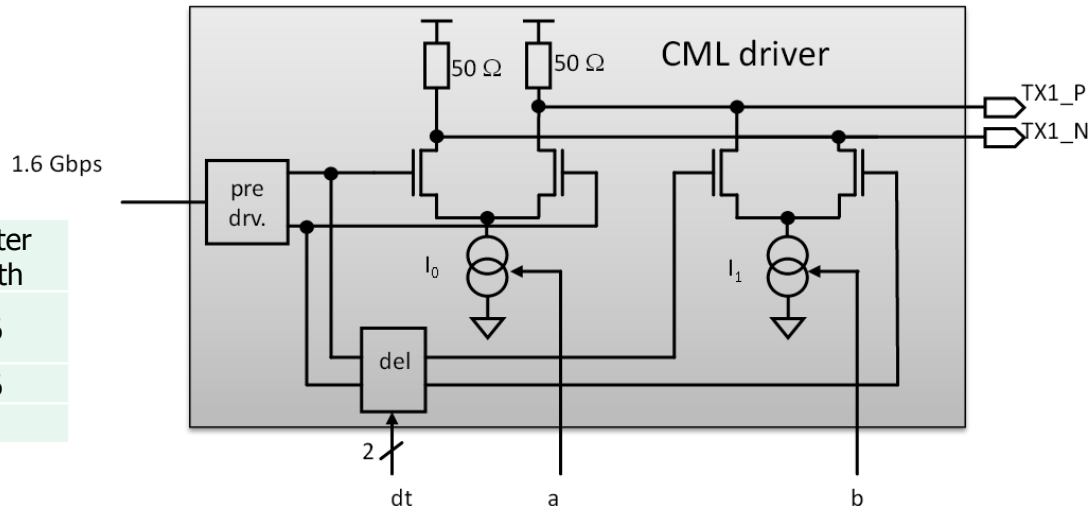
- Verilog simulation to make sure that the Switcher sequence is correct
- Switcher behavior was verified on hybrid4 test board



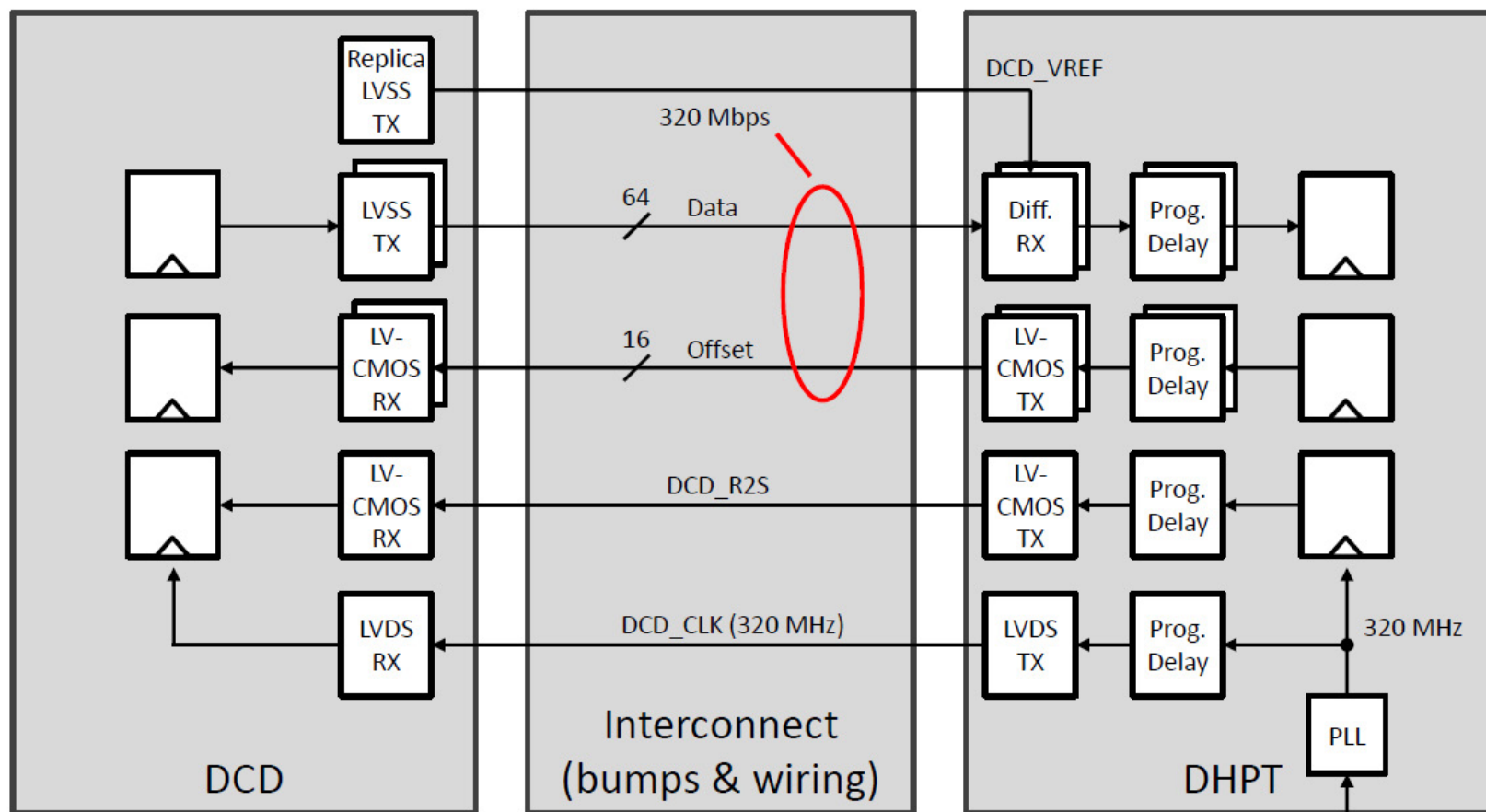
DHPT serial link – parameters of the pre-emphasis

with this scan the parameters for the pre-emphasis are determined

	Register Name	Register Length
a	IDAC CML TX BIAS	256
b	IDAC CML TX BIASD	256
c (dt)	pll cml dly sel	4



● DCD <-> DHPT communication – timing adjustment



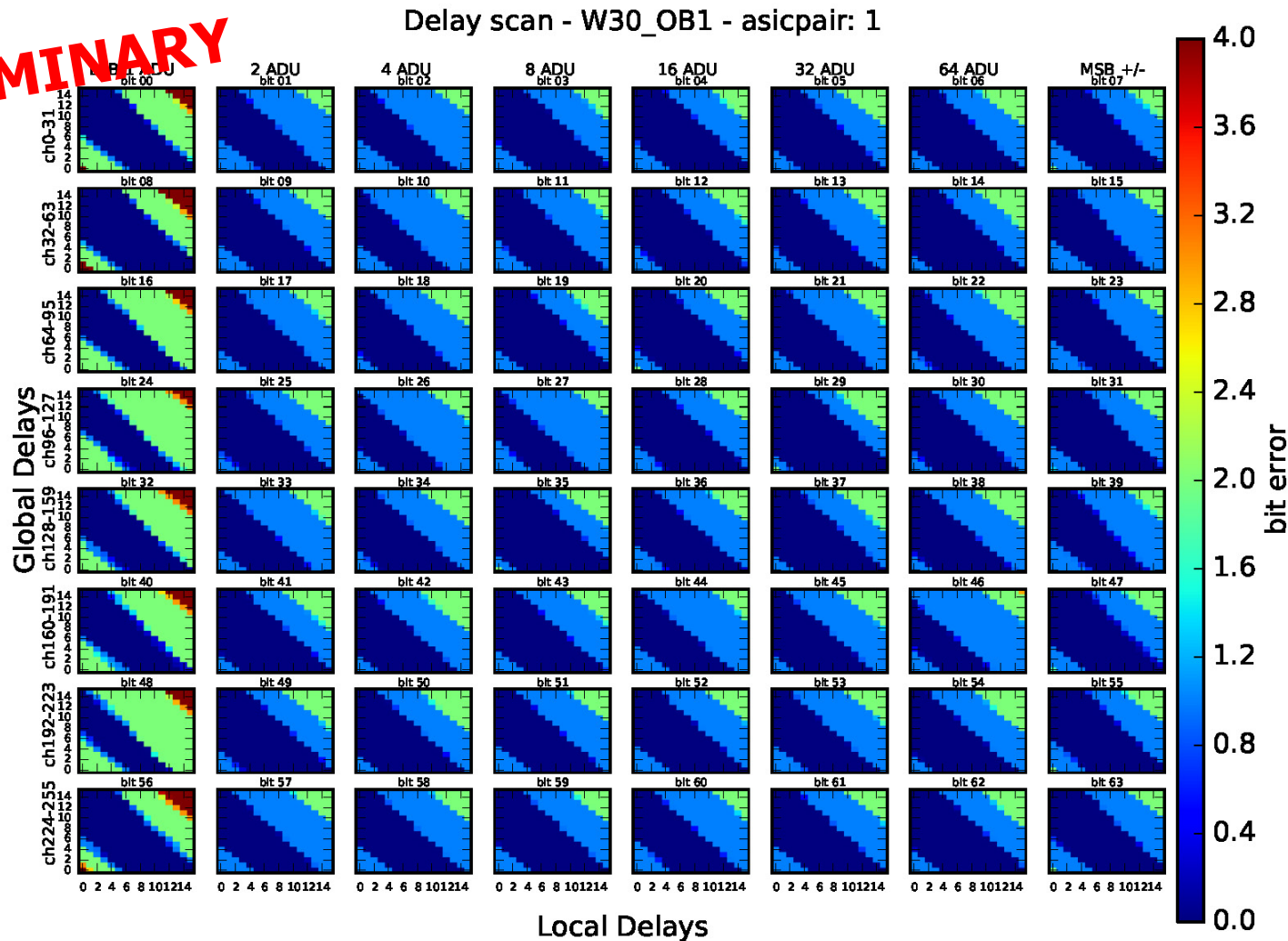
8 links with 8 data + 2 offsets bits each
 ADC sample rate = 10MHz
 32 ADCs per link → 320 Mbps

scan the parameters of the delay elements to do the phase adjustment at the DHPT receivers

GCK
 (80 MHz)

- DCD <-> DHPT communication – timing adjustment

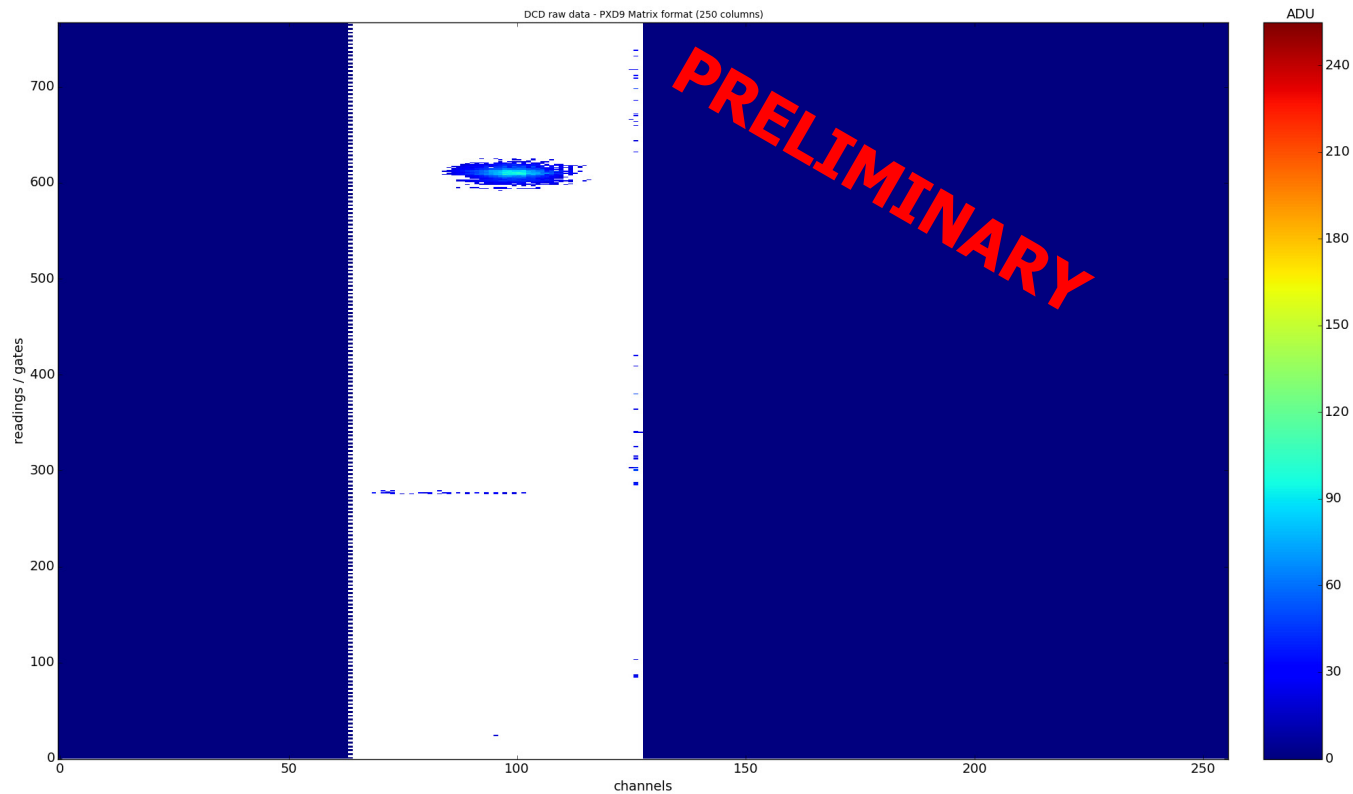
PRELIMINARY



PXD9 – delay element scan @ 250Mbps

- Measure DEPFET response (Source, Laser spot, homogeneously illuminated)

PXD9 W30-OB1



- Laser Spot in the area between SW5 and SW6
- Zero Suppressed read-out of DHPT2 only

● PXD9 Pilot Verification Plan @ BPAC



To verify the routing of the 3 metal layers of the PXD9 module the following measurements have to be done:

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	pedestal/noise all DCDs	DHPT serial link IBERT	pedestal compression				
		DHPT serial link oscilloscope	Cd109 spectrum				
		DCD <-> DHPT (delay)	Laser spot				
		sampling point scan					
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